			a	
L Number	Hits		DB	Time stamp 2004/04/23 19:43
1	3536	((257/48) or (324/158.1) or (324/501) or (438/18)).CCLS.	USPAT; US-PGPUB	2004/04/23 19:43
2	687	(((257/48) or (324/158.1) or (324/501) or	USPAT;	2004/04/23 19:46
-	00,	(438/18)).CCLS.) and (CMOS CMOSFET MOS	US-PGPUB;	2004/04/23 13.40
		MOSFET NMOS NMOSFET PMOSFET PMOS)	EPO; JPO;	
		,	DERWENT;	
			IBM_TDB	
-	0	(324/158).CCLS.	USPAT;	2004/04/23 18:36
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
	3960	324/158\$3.ccls.	IBM_TDB USPAT;	2002/06/28 21:17
-	3900	324/13633.CCIS.	US-PGPUB;	2002/00/28 21.17
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
-	3960	324/158.\$3.ccls.	USPAT;	2002/06/28 21:17
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
		lvp.ti,ab. and 257/\$6.ccls.	IBM_TDB USPAT;	2002/06/28 21-20
-	١	1 vp. c1, ab. and 25//\$6.cc18.	US-PGPUB;	2002/06/28 21:20
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
-	2	lvp.ti,ab. and probe	USPĀT;	2002/06/28 21:20
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
_	24	lvp.ti,ab.	IBM_TDB USPAT;	2002/06/28 21:21
	2.1	110.01,40.	US-PGPUB;	2002/00/20 21.21
}			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	4741	((257/48).CCLS.) or 324/158.\$3.ccls.	USPAT;	2002/06/29 12:55
l			US-PGPUB;	
			EPO; JPO; DERWENT;	
			IBM TDB	
_	7	(((257/48).CCLS.) or 324/158.\$3.ccls.) and	USPAT;	2003/08/05 15:36
[(mosfet or cmosfet or nmosfet or pmosfet	US-PGPUB;	
		or cmos or nmos or pmos) and (test or	EPO; JPO;	
]		testing or diagnostic) near12 laser	DERWENT;	
] _	8	((/257/48) CCTC) on 224/150 62 and)	IBM_TDB USPAT;	2002/06/20 12:01
-	ď	(((257/48).CCLS.) or 324/158.\$3.ccls.) and (mosfet or cmosfet or nmosfet or pmosfet	US-PGPUB;	2002/06/29 13:01
		or cmos or nmos or pmos) and (test or	EPO; JPO;	
		testing or diagnostic) near12 (optic or	DERWENT;	
		optical)	IBM_TDB	
-	2	(((257/48).CCLS.) or 324/158.\$3.ccls.) and	USPĀT;	2002/06/29 13:08
		(mosfet or cmosfet or nmosfet or pmosfet	US-PGPUB;	
	,	or cmos or nmos or pmos) and (test or	EPO; JPO;	
		testing or diagnostic) near12 (pn adj junction)	DERWENT;	
_	26	(((257/48).CCLS.) or 324/158.\$3.ccls.) and	IBM_TDB USPAT;	2002/06/29 13:15
	20	(mosfet or cmosfet or nmosfet or pmosfet	US-PGPUB;	2002/00/25 13.13
		or cmos or nmos or pmos) and (test or	EPO; JPO;	
		testing or diagnostic) and (pn adj	DERWENT;	
		junction or p-n adj junction or	IBM_TDB	
	_	pn-junction)		0000/06/55 55 :=
-	3	laser near12 diagnostic near12 (np adj	USPAT;	2002/06/29 13:17
		junction or n-p junction or np-junction)	US-PGPUB; EPO; JPO;	
			DERWENT;	
			IBM TDB	
				L

	16	laser near12 (test or testing) near12 (np	USPAT;	2002/06/29 17:33
		adj junction or n-p junction or	US-PGPUB; EPO; JPO;	
		np-junction)	DERWENT;	
			IBM TDB	
_	11	tsang.in. and kash.in.	USPAT;	2002/06/29 17:40
			US-PGPUB;	
			EPO; JPO;	
	1		DERWENT;	
	227	(324/E01) CCI C	IBM_TDB	2002/06/29 17:41
_	327	(324/501).CCLS.	USPAT; US-PGPUB;	2002/06/29 17:41
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	801	(257/48).CCLS.	USPAT;	2002/06/29 18:10
			US-PGPUB;	
			EPO; JPO;	
			DERWENT; IBM TDB	
_	3960	324/158.\$4.ccls.	USPAT;	2002/06/29 18:15
		321, 2301, 110025	US-PGPUB;	
			EPO; JPO;	
	1		DERWENT;	
	_		IBM_TDB	0000/00/05
-	8	,	USPAT;	2003/08/05 19:09
		p-n adj junction or pn-junction or p-n-junction) and (laser or optical)	US-PGPUB; EPO; JPO;	
		p-n-junction, and (laser of optical)	DERWENT;	
			IBM TDB	
_	280	(438/18).CCLS.	USPĀT;	2002/06/29 18:17
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
	913	(257/48).CCLS.	IBM_TDB USPAT;	2003/03/03 16:34
_	913	(257/46).CCLS.	US-PGPUB;	2003/03/03 10:34
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
-	91	((257/48).CCLS.) and test\$3 near6 gate	USPAT;	2003/03/03 16:36
			US-PGPUB;	
			EPO; JPO; DERWENT;	
			IBM TDB	
_	22	((257/48).CCLS.) and test\$3 near6 gate and	USPAT;	2003/03/03 16:38
!		(cmos or cmosfet)	US-PGPUB;	111, 30, 10 20,00
			EPO; JPO;	
			DERWENT;	
	_	(/257/40) 0010) +	IBM_TDB	2002/02/02 17 17
-	3	((257/48).CCLS.) and test\$3 near6 gate and (cmos or cmosfet) and (laser or	USPAT; US-PGPUB;	2003/03/03 17:15
		irradiat\$3)	EPO; JPO;	
	1		DERWENT;	
			IBM_TDB	
-	0	(terminal production of the control of the contro	USPĀT;	2003/03/03 17:16
	ļ	near6 gate and (cmos or cmosfet) and	US-PGPUB;	
	İ	(laser or irradiat\$3)	EPO; JPO;	
			DERWENT;	
_	0	((257/48).CCLS.) and optical near3 prob\$3	<pre>IBM_TDB USPAT;</pre>	2003/03/03 17:17
		near6 gate and (cmos or cmosfet)	US-PGPUB;	2003,03,03
		. , , ,	EPO; JPO;	
]			DERWENT;	
]	_	440584404	IBM_TDB	
-	0	(1===, ==, =====, =====================	USPAT;	2003/03/03 17:18
[irradiat\$3) near6 prob\$3 near6 gate	US-PGPUB;	
]			EPO; JPO; DERWENT;	
			IBM TDB	
	 	<u></u>		L

-	33	((257/48).CCLS.) and prob\$3 near6 gate	USPAT;	2003/03/03 17:19
			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB	
_	31	(((257/48).CCLS.) and prob\$3 near6 gate)	USPAT;	2003/03/03 17:20
		not (((257/48).CCLS.) and test\$3 near6	US-PGPUB;	
		gate and (cmos or cmosfet))	EPO; JPO;	
			DERWENT;	
			IBM TDB	1
_	24	((257/48).CCLS.) and laser near6 (test\$3	USPAT;	2003/03/03 17:21
		or prob\$3)	US-PGPUB;	İ
		-	EPO; JPO;	
		,	DERWENT;	
			IBM TDB	
-	38	((257/48).CCLS.) and (optical or laser)	USPAT;	2003/03/03 17:26
		near6 (test\$3 or prob\$3)	US-PGPUB;	
		•	EPO; JPO;	
	1		DERWENT;	
			IBM TDB	
-	1	((257/48).CCLS.) and (lvp or laser adj	USPAT;	2003/03/03 17:27
		voltage adj probe)	US-PGPUB;	
	1	, , , , , , , , , , , , , , , , , , ,	EPO; JPO;	
			DERWENT;	
	[IBM TDB	
_	33	(lvp or laser adj voltage adj probe) and	USPAT;	2003/03/03 17:28
	""	(mos or cmos or mosfet or cmosfet)	US-PGPUB;	2003/03/03 17:20
		(MOD OI OMODICE)	EPO; JPO;	
	1		DERWENT;	
			IBM TDB	
1_	3	(lvp or laser adj voltage adj probe) and	USPAT;	2003/03/03 17:29
1		(mos or cmos or mosfet or cmosfet) and	US-PGPUB;	2003/03/03 17:23
		(test\$3 or prob\$3) near6 gate	EPO; JPO;	
		(testys of probys) heard gate	DERWENT;	
			IBM TDB	
1_	44	 (lvp or laser adj voltage adj	USPAT;	2003/03/03 20:39
	44	probing).ti,ab,clm.	US-PGPUB;	2003/03/03 20:39
		probing/.tr,ab,cim.	EPO; JPO;	
	į		DERWENT;	
		*	IBM TDB	
_	l 0	(back-side or backside or back adj side)	USPAT;	2003/03/04 09:54
	Ĭ	near3 (lvp or laser adj voltage adj	US-PGPUB;	2003/03/04 09:54
	i	(probing or probe))	EPO; JPO;	
		(probing or probe)	DERWENT;	
			IBM TDB	
_	1	(back-side or backside or back adj side)	USPAT;	2003/03/04 10:05
	1	near12 (lvp or laser adj voltage adj	US-PGPUB;	2003/03/04 10:05
		(probing or probe))	EPO; JPO;	
		't-corna or brose',	DERWENT;	
			IBM TDB	
_	1	"6428718".PN.	USPAT	2003/03/04 09:57
_	· ·	"6403439".PN.	USPAT	2003/03/04 09:57
1_			USPAT;	2003/03/04 10:03
		probe)) and (cmos or cmosfet)	US-PGPUB;	2003/03/04 10.39
		production of one of the production	EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	1	"6331453".PN.	USPAT	2003/03/04 10:09
_		non-invasive near3 optical near12 (cmos or	USPAT;	2003/03/04 10:09
	1	cmosfet)	US-PGPUB;	2000,00,00, 10.15
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	13	reverse adj voltage near6 (cmos or	USPAT;	2003/03/04 11:01
	13	cmosfet)	US-PGPUB;	2003/03/04 11:01
			EPO; JPO;	
			DERWENT;	
			IBM TDB	
<u> </u>			10D	

_	1	reverse adj voltage near6 (cmos or	USPAT;	2003/03/04 11:02
		cmosfet) and (laser adj voltage adj	US-PGPUB;	
		(probing or probe))	EPO; JPO;	
			DERWENT;	
i			IBM_TDB	
ļ -	11		USPAT;	2003/03/04 11:06
		cmosfet) and (test\$3 or prob\$3)	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
			IBM_TDB USPAT;	2003/03/04 12:00
-	2	reverse adj voltage near6 (cmos or cmosfet) and (test\$3 or probe or probing)	US-PGPUB;	2003/03/04 12:00
		Chostet) and (test\$3 of probe of probing)	EPO; JPO;	
			DERWENT;	
			IBM TDB	
_	2	("6084267").PN.	USPAT;	2003/03/04 12:00
		,	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	,
			IBM_TDB	
-	11	((1===), =====)	USPAT;	2003/08/05 10:57
		(mosfet or cmosfet or nmosfet or pmosfet	US-PGPUB;	
		or cmos or nmos or pmos) and (test or	EPO; JPO;	
		testing or diagnostic) near12 laser	DERWENT;	
			IBM_TDB	
-	1		USPAT	2003/08/05 15:37
-	3018	324/158\$3.ccls. 257/48.ccls. 438/18.ccls.	USPAT;	2003/08/05 19:09
	77	(324/158\$3.ccls. 257/48.ccls.	US-PGPUB USPAT;	2003/08/05 19:12
-	''	438/18.ccls.) and (lvp laser adj voltage	US-PGPUB;	2003/08/03 19:12
		adj probe laser-voltage-probe laser adj	EPO; JPO;	
		voltage-probe (laser near12 (test\$3	DERWENT;	
		diagnostic(1)))	IBM TDB	
_	100	yoshida.in. and eiji.in.	USPAT;	2003/08/06 08:42
		,	US-PGPUB	,
-	1	yoshida.in. and eiji.in. and	USPAT;	2003/08/06 08:43
		transistor.clm. and laser.clm.	US-PGPUB	
-	6	1	USPAT;	2003/10/19 15:14
		and gate and laser	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	·
	2	("6137295").PN.	IBM_TDB USPAT;	2003/10/19 15:15
	_	(0157255).IN:	US-PGPUB;	2003/10/13 13.13
			EPO; JPO;	
1			DERWENT;	
			IBM TDB	
-	6	392925.ap.	USPAT;	2003/10/19 15:27
1			US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
-			IBM_TDB	
1 -	5806	((324/158.1) or (324/501) or	USPAT;	2003/10/19 15:27
		(257/48)).CCLS.	US-PGPUB;	
			EPO; JPO;	
			DERWENT;	
_	10	(((324/158.1) or (324/501) or	IBM_TDB USPAT;	2003/10/19 15:41
		((324/136.1) of (324/301) of (257/48)).CCLS.) and laser near20 junction	US-PGPUB;	2003/10/19 13.41
}		(EPO; JPO;	
			DERWENT;	
			IBM TDB	
-	398	(438/18).CCLS.	USPĀT;	2003/10/19 15:41
			US-PGPUB;	
		·	EPO; JPO;	
			DERWENT;	
	_	///20/10\ 007.0 \	IBM_TDB	0000/07/77
-	2	((438/18).CCLS.) and laser near20 junction	USPAT;	2003/10/19 15:41
			US-PGPUB;	
			EPO; JPO;	
			DERWENT; IBM TDB	
L	L	<u> </u>	TDM IDD	L

			·	· · · · · · · · · · · · · · · · · · ·
-	6	lvp.ti,ab,clm. and probe	USPAT;	2003/10/19 15:56
]		US-PGPUB; EPO; JPO;	
			DERWENT;	
			IBM TDB	
-	437	cmos.ti,ab,clm. and drain near3 (connect	USPAT	2003/10/19 18:18
		connected) near3 source and common near2		
İ	109	(source drain) cmos.ti,ab,clm. and drain near3 (connect	USPAT	2003/10/19 18:19
	103	connected) near3 source and common near2	OSIAI	2003/10/13 10:13
		(source drain) and 257/\$9.ccls.		
-	299	nmos near12 pmos and common adj (source	USPAT;	2003/10/19 19:45
		drain) and 257/\$9.ccls.	EPO; JPO	0000/10/10 10:40
-	0	dillinger.in. and protection and gate	USPAT; EPO; JPO;	2003/10/19 19:48
	-		DERWENT	•
-	74	latchup and testing and (257/\$9.ccls.	USPAT;	2003/10/19 19:53
		438/\$9.ccls.)	EPO; JPO;	
	9	(latchup latch-up) near12 testing and	DERWENT	2003/10/19 20:10
		(257/\$9.ccls. 438/\$9.ccls.)	EPO; JPO;	2003/10/19 20:10
		(22., ,)	DERWENT	
-	1012	(257/48).CCLS.	USPAT;	2003/10/19 20:11
	1		US-PGPUB;	
	1		EPO; JPO; DERWENT;	
			IBM TDB	
-	1012	(257/48).CCLS.	USPAT;	2003/10/19 20:11
			US-PGPUB;	
			EPO; JPO; DERWENT;	
			IBM TDB	
_	542	(257/48).CCLS.	USPAT	2003/10/19 20:13
-	27	((257/48).CCLS.) and pmos and nmos	USPAT;	2003/10/19 20:13
			US-PGPUB;	
			EPO; JPO; DERWENT;	
			IBM TDB	
-	6357	324/158.1	USPAT;	2004/01/04 18:28
			US-PGPUB; EPO; JPO;	
			DERWENT;	
			IBM TDB	
-	655	324/501	USPAT;	2004/01/04 18:28
	[US-PGPUB;	
			EPO; JPO; DERWENT;	
			IBM_TDB	
-	1900	257/48	USPĀT;	2004/01/04 18:28
1			US-PGPUB;	
1			EPO; JPO; DERWENT;	
			IBM TDB	
-	8493	324/158.1 324/501 257/48	USPAT;	2004/01/04 18:28
			US-PGPUB;	
			EPO; JPO; DERWENT;	
			IBM TDB	
] -	14	(USPAT;	2004/01/04 18:30
		voltage adj probe lvp laser adj	US-PGPUB;	
		diagnostic\$1 laser adj test\$3)	EPO; JPO; DERWENT;	
			IBM TDB	
-	2	("5286656").PN.	USPAT;	2004/04/23 19:42
			US-PGPUB;	
			EPO; JPO; DERWENT;	
			IBM TDB	
	ı		1001_100	L